Industrial-Strength Model-Based Testing - State of the Art and Current Challenges

Jan Peleska University of Bremen Verified Systems International GmbH MBT Workshop, Rome, 2013-03-17

C O M P A S S





Overview

- Model-based testing
- A reference tool
- Modelling aspects
- Requirements, test cases and strategies
- Conclusion challenges

Model-based testing

- A reference tool
- Modelling aspects
- Requirements, test cases and strategies
- Conclusion challenges

- Model-based testing (MBT) as defined in Wikipedia
 - "Model-based testing is application of Model based design for designing and optionally also executing artefacts to perform <u>software testing</u>. Models can be used to represent the desired behaviour of a System Under Test (SUT), or to represent testing strategies and a test environment."

- Model-based testing (MBT) as defined in Wikipedia
 We would say:
- "Model-based testing system or software testing application of Model based designing and optionally also executing artefacts to perform software testing. Models can be used to represent the desired behaviour of a System Under Test (SUT), or to represent testing strategies and a test environment."

Let's analyse this definition

- "Apply model-based design": use modelling formalism to specify any testrelated information
 - "Models ...represent desired behaviour of ... SUT": Just specify the desired capabilities of the SUT
 - ... or, alternatively ...

- "Models ... represent testing strategies and a test environment":
 - It is explicitly modelled how test cases and associated test data should be produced and
 - how these should interact with the SUT
 - Here MBT helps to
 - represent test cases in a concise and intuitive way
 - transform test cases and data into executable test procedures

Our MBT Approach

Instead of writing test procedures,

- develop a test model specifying expected behaviour of SUT → the first MBT variant
- use generator to identify "relevant" test cases from the model and calculate concrete test data
- generate **test procedures** fully automatic
- perform tracing requirements ↔ test cases in a fully automatic way

Model-based testing

• A reference tool

- Modelling aspects
- Requirements, test cases and strategies
- Conclusion challenges

Reference Tool RT-Tester

- Supports all test levels from unit to system integration testing
- Software tests and hardware-in-theloop tests
- Test projects may combine handwritten test procedures with automatically generated procedures

The tool capabilities are presented here to stimulate benchmarking activities

















Modelling Tool





- Model-based testing
- A reference tool

Modelling aspects

- Requirements, test cases and strategies
- Conclusion challenges

- The controversy about modelling formalisms is unlikely to come to an end in the foreseeable future
- Domain-specific language methodology even suggests that productivity and quality are improved, if formalisms optimised for their application domains are used

Modelling formalisms supported by RT-Tester

- Timed CSP
- CML COMPASS Modelling Language
- Timed Moore Automata
- UML
- SysML

• UML

- Composite structure diagrams
- Interfaces
- Classes and operations
- State machines with timers

- SysML
 - Block definition diagrams
 - Internal block diagrams
 - Item flows
 - State machines with timers
 - Operations
 - Requirements
 - <<satisfy>> relationship between requirements and model elements

Case Study With SysML

- Simplified version of the turn indication and emergency flashing function in Daimler vehicles
- Full model available under

http://www.mbt-benchmarks.org

- → Benchmarks
- → Turn Indicator Model Rev. 1.4

Turn Indication Function

Requirement	Description
REQ-001	Flashing requires more than 80% of nominal input voltage
REQ-002	Flashing is performed with 340ms/320ms on-off periods
REQ-003	Turn indication lever switched to 1 results in left-hand side flashing
•••	•••

Test Model



SUT and TE







Model Semantics

- Based on Kripke Structures
- Equivalent to alternative operational semantics based on labelled transition systems

 $K = (S, S_0, R, L)$ S : State space $S_0 \subseteq S : \text{Initial states}$ $R \subseteq S \times S : \text{Transition relation}$ $L : S \to 2^{AP} : \text{Labelling function}$ AP : Atomic propositions

Idealised conformance relation

 For any timed input trace, SUT should produce the same outputs as the model

 $\forall i \in \{0, \dots, n\} : s_i|_{I \cup O \cup \{\hat{t}\}} = s'_i|_{I \cup O \cup \{\hat{t}\}}$

 $s_0.s_1...s_n$: Model trace $s'_0.s'_1...s'_n$: SUT trace

Idealised conformance relation is justified when

- Interfaces are non-blocking
- Most-recent values of SUT outputs are always available
- Each sequential SUT component is deterministic
- Synchronous concurrency semantics applies
- Application in RT-Tester: testing SCADE software

Conformance relations in presence of non-determinism – required for

- asynchronous distributed control systems
- in presence of SUT outputs behaving non-deterministically over certain periods of time – often due to underspecification

Non-determinism as handled in RT-Tester

 Admissible output deviations

$$|s'(y) - s(y)| \le \varepsilon_y$$

- Admissible output latency
- Admissible early changes
- Time-bounded nondeterministic assignment
- Model transformation
 SUT → Test oracle

$$s'(\hat{t}) - s(\hat{t}) \le \delta_y^0$$

$$s(\hat{t}) - s'(\hat{t}) \le \delta_y^1$$

$$y = UNDEF(t,c);$$

Model Transformation for Test Oracles

Model component with associated state machine ...

 C_i

Transformed into modified state machine and test oracle

Model Transformation for Test Oracles

SUT component with associated state machine

Transformed model consisting of transformed state machine and oracle

Model Transformation for Test Oracles

a: internal model variable

x: input

 For a given input sequence and resulting SUT I/O trace, the transformed system should never assume an error state in any of its test oracles.

$$\begin{aligned} \forall s'_0 \dots s'_n, s_0^+ \dots s_n^+ : (\forall i = 0, \dots, n, y \in O: \\ s'_i|_{I \cup \{\hat{t}\}} = s_i^+|_{I \cup \{\hat{t}\}} \wedge s'_i(y) = s_i^+(y')) \Rightarrow \\ (\forall i = 0, \dots, n, j = 1, \dots, k: \neg s_i^+(\mathcal{O}_j.\texttt{error})) \end{aligned}$$

- Model-based testing
- A reference tool
- Modelling aspects

Requirements, test cases and strategies

Conclusion – challenges

Requirements

 Each requirement is reflected by set of model computations

 $\pi = s_0.s_1.s_2\ldots$

 Computation sets can be characterised by Linear Temporal Logic (LTL)

 $\mathbf{G}\phi:$ Globally ϕ holds on path π

 $\mathbf{X}\phi$: In the next state on path π , formula ϕ holds.

 $\mathbf{F}\phi:$ Finally ϕ holds on path π

 $\phi \mathbf{U} \psi : \mathbf{F} \psi$ and ϕ holds on path π until ψ is fulfilled

Requirements – LTL Examples

• REQ-001. Flashing requires sufficient voltage

 $\mathbf{X}(\neg(\text{FlashLeft} \lor \text{FlashRight}) \mathbf{U} \text{ Voltage} > 80))$

 $G(Voltage \le 80 \Rightarrow$

• Reduced to model computations

 $G(Voltage \le 80 \Rightarrow X(Idle U Voltage > 80))$

• Finally $F(Voltage \le 80)$

Requirements – LTL Examples

- Requirements specification is simplified by referring to internal model symbols
- REQ-002. Flashing with 340/320ms on-off-periods

 $\mathbf{F}(\text{OFF} \wedge \mathbf{X} \text{ ON})$

Requirements Tracing to Model Elements

 Simple requirements tracing: every computation finally covering one model element of a given collection contributes to the requirement

$\mathbf{F} \langle \mathrm{State} \ \mathrm{Formula} \rangle$

• Simple requirements are reflected by formulas satisfying $\mathbf{F}\left(\bigvee_{i=0}^{h}\phi_{i}\right)$

Requirements Tracing – Complex Requirements

- Computations contributing to complex requirements require full LTL expressions
- Insert LTL formula in constraint
- Link constraint to requirement via <<satisfy>> relation

Requirement	Constraint
REQ-001 Flashing requires	$\mathbf{F}(\text{Voltage} \le 80)$
sufficient voltage	
REQ-002 Flashing with	$\mathbf{F}(\mathrm{OFF}\wedge\mathbf{X}\mathrm{ON})$
340 ms/320 ms on-off periods	
REQ-003 Switch on turn in-	$\mathbf{F}(\text{FlashLeft} = 1 \land \text{FlashRight} = 0)$
dication left	
REQ-004 Switch on turn in-	$\mathbf{F}(\text{FlashLeft} = 0 \land \text{FlashRight} = 1)$
dication right	
REQ-005 Emergency flash-	$\mathbf{F}(\text{EMER}_OFF \land \text{TurnIndLvr} > 0 \land \text{EmerFlash})$
ing on overrides left/right	
flashing	
REQ-006 Left-/right flashing	F TURN_IND_OVERRIDE
overrides emergency flashing	
REQ-007 Resume emergency	$\mathbf{F}(\text{TURN}_{\text{IND}}_{\text{OVERRIDE}} \land \mathbf{X}_{\text{EMER}}_{\text{ACTIVE}})$
flashing	
REQ-008 Resume turn indi-	$\mathbf{F}(\text{EMER}_\text{ACTIVE} \land \neg \text{EmerFlash} \land \text{TurnIndLvr} > 0)$
cation flashing	
REQ-009 Tip flashing	$\mathbf{F}(\text{Voltage} > 80 \land \neg(\text{Left} \lor \text{Right}) \land$
	$Left1 + Right1 = 1 \land FlashCtr < 3)$

Test Cases

- Test cases are finite witnesses of model computations
- Trace = finite prefix of a computation
- If computation satisfies LTL formula associated with a requirement, trace prefixes must at least not violate this formula
- Some formulas can only be verified on an infinite computation (liveness formulas, e.g. fairness properties)
- But these properties can only be partially verified by testing

Trace Semantics for LTL Formulas

 $\langle \varphi \rangle_i^k$ states that formula φ holds in trace segment $s_i \cdot s_{i+1} \dots s_k$ of a trace $s_0 \dots s_k$

•
$$\langle \mathbf{G} \varphi \rangle_0^k = \bigwedge_{i=0}^k \langle \varphi \rangle_i^k$$

•
$$\langle \mathbf{X} \varphi \rangle_i^k = \langle \varphi \rangle_{i+1}^k$$

•
$$\langle \varphi \mathbf{U} \psi \rangle_i^k = \langle \psi \rangle_i^k \vee (\langle \varphi \rangle_i^k \wedge \langle \varphi \mathbf{U} \psi \rangle_{i+1}^k)$$

•
$$\langle \mathbf{F}\psi \rangle_i^k = \langle \text{true } \mathbf{U} \psi \rangle_i^k$$

Test Data Computation

• LTL formulas interpreted on finite traces can be transformed into first order expressions

$$tc \equiv J(s_0) \wedge \bigwedge_{i=0}^{n} \Phi(s_i, s_{i+1}) \wedge G(s_0, \dots, s_{n+1})$$

 Recall. These formulas can be solved by an SMT solver

Model Coverage Strategies

Strategies currently realised in RT-Tester

- Basic control state coverage
- Transition coverage
- MC/DC coverage
- Hierarchic transition coverage
- Equivalence class and boundary value coverage
- Basic control state pairs coverage
- Interface coverage
- Block coverage

Model Coverage Strategies

- Example. Hierarchic transition coverage for state machine FLASH_CTRL
- $tc_1 \equiv \mathbf{F}(\text{EMER_OFF} \land \text{EmerFlash})$
- $tc_{2} \equiv \mathbf{F}(\text{EMER}_\text{ACTIVE} \land \text{TurnIndLvr} \neq 0 \land$ $((\text{TurnIndLvr} = 1) \neq \text{Left1} \lor$ $(\text{TurnIndLvr} = 2) \neq \text{Right1}))$
- $tc_6 \equiv \mathbf{F}(\neg \text{EmerFlash} \land \text{TURN_IND_OVERRIDE} \land$ TurnIndLvr $\neq 0$)

Requirements Tracing

- If some model elements are linked to requirement R via <<satisfy>> relationship, then model coverage test cases tc covering these elements are automatically traced to R:
- *tc* <<verify>> *R*

Requirements Tracing

If requirement R is characterised by complex LTL formula ϕ , proceed as follows

- Transform ϕ into some disjunctive form $\phi \equiv \bigvee_{i=0}^{m} \phi_i$
- For each ϕ_i associate test cases separately:

- If
$$\psi \Rightarrow \phi_i$$
 and $(tc \equiv \psi)$, add $(tc \equiv \psi) \ll \mathsf{verify} \gg \mathsf{R}$

- If $\psi \not\Rightarrow \phi_i$ and $\phi_i \not\Rightarrow \psi$, but $\psi \wedge \phi_i$ has solution, add new test case $(tc' \equiv \psi \wedge \phi_i) \ll verify \gg R$.

- If
$$((tc_1 \equiv \mathbf{F}\psi_1) \ll \text{verify} \gg \mathbb{R} \text{ or}$$

 $(tc_2 \equiv \mathbf{F}\psi_2) \ll \text{verify} \gg \mathbb{R})$ and
 $tc' \equiv \mathbf{F}(\psi_1 \wedge \psi_2)$ has a solution,
add $tc' \ll \text{verify} \gg \mathbb{R}$.

Requirements Tracing

Example. Refined test cases for REQ-002 (Flashing with 340/320ms on-off period)

$$tc_7 \equiv \mathbf{F}(\text{OFF} \land (\mathbf{XON}))$$

- $tc_8 \equiv \mathbf{F}(OFF \land (\mathbf{XON}) \land TurnIndLvr = 1)$
- $tc_9 \equiv \mathbf{F}(OFF \land (\mathbf{XON}) \ge 320 \land TurnIndLvr = 2)$
- $tc_{10} \equiv \mathbf{F}(\text{OFF} \land (\mathbf{XON}) \ge 320 \land \text{EMER_ACTIVE})$
- $tc_{11} \equiv \mathbf{F}(OFF \land (\mathbf{XON}) \land TURN_IND_OVERRIDE)$

Combinatorial explosion problem

Test Case Reduction

- Reduction is inevitable for real-world systems
- Reduction should be justified
- Justification should conform to V&V standards, such as
 - RTCA DO-178C
 - CENELEC EN 50128:2011
 - ISO 26262

Test Case Reduction

Option I. No further test cases when

- all requirements have been covered by at least one test case
- code coverage required by the standard has been achieved
- This option is appropriate for RTCA
 DO-178C, if code coverage measurement is possible

Test Case Reduction

Option 2. Test case selection according to assurance level (= criticality)

- Level 3: interface tests, basic control state coverage
- Level 2: + transition coverage
- Level I: + basic control state pairs coverage, hierarchic transition coverage, MC/DC coverage, first-level test case refinements as introduced above, second-level refinements if new conjuncts have impact on the requirement

- Model-based testing
- A reference tool
- Modelling aspects
- Requirements, test cases and strategies

Conclusion – Challenges

Challenges – Modelling

- Testing must not be delayed by modelling
 - Incremental modelling and learning from concrete executions
- Complexity
 - Some Abstraction, equivalence class partitioning
- Test model development requires higher skills than test script programming
 - Management issue: need fewer engineers with higher competence

Challenges – Test Cases / Strategies

Coping with state space complexity in Systems of Systems (SoS)

- Associate mission threads of constituent systems with equivalence classes
- On SoS level, identify "relevant" class combinations by means of impact analysis

Challenges – SoS-Specific

 Dynamic changes of system configuration run-time acceptance

testing required

- Under-specification and nondeterminism due to abstractions in contracts
- Justification of test strategies by proof of exhaustiveness: still possible on this level?

Contributors ...

Contributors ...

Acknowledgements. This presentation has been elaborated in the context of the EU FP7 COMPASS project under grant agreement no.287829.